
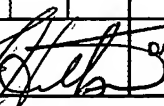


Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MI22-2144	SERIAL NO. 10/669,667
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>		APPLICANT: Li Li et al.	
		FILING DATE September 23, 2003	GROUP 1765

U.S. PATENT DOCUMENTS							
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
F.H.	AA	2003/0064607 A1	4/3/2003	Leu et al.			
↑	AB	2003/0205823 A1	11/6/2003	Leu et al.			
	AC	2003/0032281 A1	2/13/2003	Werkhoven et al.			
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F.H.	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
F.H.	AI	WO 0166832	9/13/2001	PCT/Werkhoven et al.				
F.H.	AK	EP 1107302	6/13/2001	EPO/Huang et al.				
	AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
F.H.	AM		"Digital Chemical Vapor Deposition of SiO ₂ using a Repetitive Reaction of Triethylsilane/Hydrogen and Oxidation"; Sakaue et al.; Japanese Journal of Applied Physics, Vol. 30, No. 1B; January 1990; pp. L124-L127.
F.H.	AN		PCT/US2004/029478; Filed September 9, 2004; Search Report.
EXAMINER:  DATE CONSIDERED: 11/15/05			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>			

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: LI Li et al.				
				FILING DATE September 23, 2003		GROUP 1722		
U.S. PATENT DOCUMENTS								
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
F.H.	AA	6,511,539 B1	01/28/03	Raaijmakers	—	—	—	
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	AE							
	AF							
	AG							
	AH							
	AI							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ							
	AK							
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AM							
	AN							
	AO							
EXAMINER <i>[Signature]</i>		DATE CONSIDERED <i>7/18/05</i>						
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